PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B-VXI-AC03  
Type: Semiconductor Device Tester  
S.N.: 13195  
Date: September 8, 2014

Basic specifications:

Output Amplitude: to +100 mA, -100 mA  
Pulse Width (FWHM): 200 ns  
Switching Time, + to -, 10%-90%: ≤ 300 ps (at mainframe)  
PRF: 1 - 10 kHz  
Jitter, Stability: OK  
Prime Power: 100-240V AC, 50-60 Hz.

Test Waveforms

With a 1N4148 installed in the AVX-CA-AR1 test jig, 40 mA/div, 2 ns/div:

\[ I_F = +100 \text{ mA}, \ I_R = -100 \text{ mA} \]

\[ \text{Measured } t_{RR} = 8.6 \text{ ns} \]

With a 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 10 ns/div:

\[ I_F = +100 \text{ mA}, \ I_R = -100 \text{ mA} \]

\[ \text{Measured } t_{RR} = 51 \text{ ns} \]
Pulse output directly from mainframe, with the test jig bypassed (2 V/div, 1 ns/div):

Shows a 10%-90% transition time of 190.4 ps.